

**Search Notes**

Application/Control No.

10/800,549

Examiner

Y. J. Han

Applicant(s)/Patent under  
Reexamination

RIBARICH ET AL.

Art Unit

2838

**SEARCHED**

Class	Subclass	Date	Examiner
323	225		
	242		
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363	25	3/65	gn

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR